# **TTT4120 Digital Signal Processing**

## **Problem Set 1**

**Peter Pham** 

2023-09-20

## **Contents**

Problem 1 - Conductivity	3
Problem 2 - The Hall Experiment	7
Part 3: Carrier Concentrations	10

### **Problem 1 - Conductivity**

a)

The conductivity of a semiconductor will depend on the doping concentration. Express the conductivity  $\sigma$  as a function of

$$\tilde{n} = \frac{n_0}{n_i}$$

where  $n_i$  is the intrinsic electron concentration,  $n_0$  is the electron concentration at thermal equilibrium.

The general equation for conductivity due to electron is

$$\sigma = q n_0 \mu_n$$

from the given function we have that

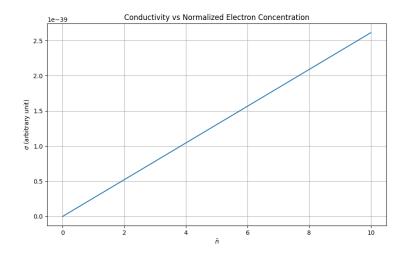
$$n_0 = \tilde{n} \cdot n_i$$

This gives us

$$\sigma = q(\tilde{n} \cdot n_i)\mu_n$$

where q is the charge of an electron,  $\tilde{n}$  is the electron concentration normalized to the intrinsic value  $n_i$  the intrinsic carrier concentration,  $\mu_n$  is the electron mobility.

Use the values of  $\mu_n$  and  $\mu_p$  for Si and plot the function for  $\tilde{n} \in [0, 10]$ . Give an intuitive explanation for the shape of the function. Do not consider the variations in the mobility with the doping concentration.



We can se that the relation between the conductivity  $\sigma$  and the electron concentration normalized to the intrinsic value is linear. It makes sense as the the conductivity increases when you n-dope the Si

b)

#### Show that the minimum conductivity is given by

$$\sigma_{\min} = 2qn_i\sqrt{\mu_n\mu_p}$$

The current density can be written in terms of mobility as

$$J_x = qn\mu_n \mathcal{E}_x$$

If both electrons and holes participate, then we must modify the equation to

$$J_x = q (n\mu_n + p\mu_p) \mathcal{E}_x = \sigma \mathcal{E}_x$$

by combining this with the product of electron and hole concentration and assuming that the conductivity is at minimum when  $n_0 = p_0 = n_i$ .

$$n_0 p_o = n_i^2$$

$$p_0 = \frac{n_i^2}{n_0}$$

Substitute this into  $\sigma$ :

$$\sigma = q(n_0\mu_n + \frac{n_i^2}{n_0}\mu_p)$$

for  $\sigma$  to be minimized,  $\frac{d\sigma}{dn_0} = 0$ 

$$\frac{d\sigma}{dn_0} = q(\mu_n - \frac{n_i^2 \mu_p}{n_0^2}) = 0$$

$$\mu_n = \frac{n_i^2 \mu_p}{n_0^2}$$

$$n_0^2 = n_i^2 \frac{\mu_p}{\mu_n}$$

$$n_0 = n_i \sqrt{\frac{\mu_p}{\mu_n}}$$

$$n_0 = n_i \sqrt{\frac{\mu_p}{\mu_n}}$$

$$p_0 = n_i \sqrt{\frac{\mu_p}{\mu_n}}$$

We substitute these values into the expression for  $\sigma$ :

$$\sigma = q(n_0\mu_n + p_0\mu_p)$$

$$\sigma = q(n_i\sqrt{\frac{\mu_p}{\mu_n}}\mu_n + n_i\sqrt{\frac{\mu_n}{\mu_p}}\mu_p)$$

$$\sigma = qn_i(\sqrt{\mu_n\mu_p} + \sqrt{\mu_n\mu_p})$$

$$\sigma_{\min} = 2qn_i\sqrt{\mu_n\mu_p}$$

Hence, the minimum conductivity  $\sigma_{\min}$  is given by  $2qn_i\sqrt{\mu_n\mu_p}$  when  $n_0=n_i\sqrt{\frac{\mu_p}{\mu_n}}$ .

The intrinsic conductivity  $\sigma_i$  for Si can be calculated using the equation:

$$\sigma_i = q n_i (\mu_n + \mu_p)$$

for silicon:

Parameter	Value
$\mu_n$ (Electron mobility in cm <sup>2</sup> /V-s)	1350
$\mu_p$ (Hole mobility in cm <sup>2</sup> /V-s)	450
$n_i$ (Intrinsic carrier concentration in cm <sup>-3</sup> )	$1.5 \times 10^{10}$
q (Elementary charge in C)	$1.6 \times 10^{-19}$
$\sigma_i$ (Intrinsic conductivity in S/cm)	$4.32 \times 10^{-2}$
$\sigma_{min}$ (Minimum conductivity in S/cm)	$3.74 \times 10^{-2}$

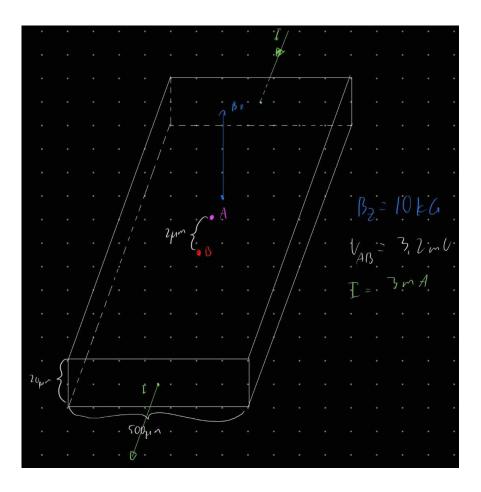
Table 1: Typical values for silicon and calculated intrinsic conductivity

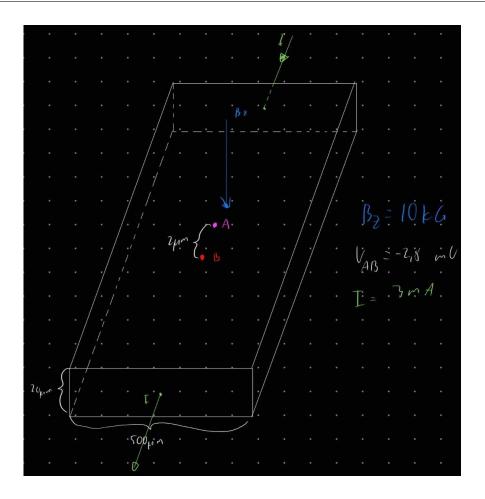
when comparing the two conductivities we can se that extrinsic doesn't necessary mean that we get a more conductivity.

### **Problem 2 - The Hall Experiment**

Hall measurements are made on a p-type semiconductor bar  $500\mu m$  wide and  $20\mu m$  thick. The Hall contacts A and B are displaced  $2\mu m$  with respect to each other in the direction of a current flow of 3 mA. The voltage between A and B with a magnetic field of 10kG ( $1kG = 10^{-5}$  Wb/cm<sup>2</sup>) pointing out of the plane of the sample is 3.2mV. When the magnetic field direction is reversed, the voltage changes to -2.8mV.

a) Draw a figure that illustrate the setup and includes all the given information. Make sure you get the correct orientation of the contacts A and B.





### b) Calculate the hole concentration and mobility.

we can get the hole concentration from the equation

$$p_0 = \frac{I_x \mathcal{B}_z}{qt V_{AB}}$$

$$p_0 = \frac{0.003 \times 10^{-4}}{1.6 \times 10^{-19} \times 2 \times 10^{-5} 0.0031} = 3.02 \times 10^{19} cm^{-3}$$

the resistivity is given by

$$\rho = \frac{\frac{V_{AB}}{I_x}}{\frac{L}{wt}}$$

$$\rho = \frac{\frac{0.0031}{0.003}}{\frac{2 \times 10^{-6}}{2 \times 10^{-5} \times 5 \times 10^{-4}}} = 0.00516\Omega m$$

the mobility is given by

$$\mu_n = \frac{1}{\rho q p_o}$$

$$\mu_n = \frac{1}{0.00516 \times 1.6 \times 10^{-19} \times 3.02 \times 10^{19}} = 40.11 \frac{cm^2}{Vs}$$

## **Part 3: Carrier Concentrations**